Proposal List of Contract Beamline Experiments in 1999B

Proosal No.	Project Leader	Title of Experiment	Beamline No.
C99B16XU-300N	HIROSE, Takayuki	X-ray Diffraction of Co alloy magnetic film	BL16XU
C99B16XU-301N	LIU, Kuang-Yu	The Crystal Structure Analysis of Lithium Oxide	BL16XU
C99B16XU-302N	TAKAHASHI, Mamoru	X-ray Scattering Study on the Structure of Ultra-thin Insulator Films	BL16XU
C99B16XU-303N	KIMURA, Shigeru	X-ray diffraction measurements for thin films of BaSrTiO3/Si and Other Materials	BL16XU
C99B16XU-304N	YAMAGUCHI, Koji	Crystallographic characterization of high-strength steel wire	BL16XU
C99B16XU-305N	KONOMI, Ichiro	XRD studies on a LiNiO2 secondary battery utilized anomalous scattering	BL16XU
C99B16XU-306N	HIRAI, You	Structure Analysis of Oxide Film Formed on Steel Surface	BL16XU
C99B16XU-307N	HIRAI, Yasuharu	STructre analysis of magnetic thin films and organic materials	BL16XU
C99B16XU-308N	AWAJI, Naoki	X-ray fluorescence and CTR scattering analyses of Si oxide films and magnetic metal films	BL16XU
C99B16XU-309N	OZAKI, Shinji	XRF Analysis of Silicon Oxide Films	BL16XU
C99B16XU-310N	HIRAI, Yasuharu	Analysis of semiconductor thin films	BL16XU
C99B16XU-311N	HIRAI, Yasuharu	Micro -analysis of thin films and organic materials	BL16XU
C99B16XU-312N	HIRAI, You	Structural Analysis of Iron Oxide Layer of Steels	BL16XU
C99B16XU-313N	LIU, Kuang-Yu	The Analysis of Very Small Quantity Impurities on Silicon Wafer	BL16XU
C99B16XU-314N	OZAKI, Shinji	Analysis of Surface Impurities on Semiconductor Wafers	BL16XU
C99B16XU-315N	KONOMI, Ichiro	Structural Analysis of GeSbTe thin films by X-ray Diffracion	BL16XU
C99B16XU-316N	DEGUCHI, Hiroshi	Structure Analysis of CoPt3 Using Anomalous X-ray Scattering	BL16XU
C99B16B2-400N	OKAMOTO, Tokuhiko	Local Structure Analysis on Y2O3 / ZrO2, LaMnO3, Ni-Co-Mn-O and BaTiO3 Some Oxides by Transmision XAFS.	BL16B2
C99B16B2-401N	HAGA, Koukichi	Structure Analyses of Electronic Materials (Er Doped lasses, GaAs wafers, and origanic EL devices)	BL16B2
C99B16B2-402N	UEHARA, Yasushi	XAFS study of dielectrics thin films (SrTiO3)	BL16B2
C99B16B2-403N	OKAMOTO, Tokuhiko	XAFS Study on LiNiO2 Secondary Batery	BL16B2
C99B16B2-404N	KUDO, Yoshihiro	The Structure Analysis of Lithium Oxide by XAFS Method	BL16B2
C99B16B2-405N	WATANABE, Takashi	Absolute measurement of the energy of x-ray absorption edges (Kedges of Cu)	BL16B2
C99B16B2-406N	HIROSE, Jun	Study of local structures of electrode materials for chemical batteries	BL16B2
C99B16B2-407N	TERANISHI, Hideaki	XAFS Measurements of Pt alloy	BL16B2
C99B16B2-408N	WATANABE, Takashi	Analysis of Microstructure of Iron Corrosion Products by SR-XAFS	BL16B2
C99B16B2-409N	TAKEMURA, Momoko	Local structure analysis of tantalum oxide films by Ta L-shell XAFS	BL16B2

C99B16B2-410N	DEGUCHI, Hiroshi	Local Structure Analysis of Perovskite and Fluorite Oxides for Solid State Oxide Fuel Cell	BL16B2
C99B16B2-411N	UEHARA, Yasushi	X-ray reflective study of ultra-thin films of silicon oxide	BL16B2
C99B16B2-412N	OHSAWA, Michio	X-ray Reflectity of Magnetic Recording Media	BL16B2
C99B16B2-413N	TAKEISHI, Shunsaku	X-ray diffraction study of Si oxide films and magnetic metal films	BL16B2
C99B16B2-414N	OKAMOTO, Tokuhiko	Local Structure Analysis on Si3N4, Pd/Fe-Co Perovuskite and Fe/ SiO2 Matarials by Fluorescoce XAFS	BL16B2
C99B16B2-415N	IZUMI, Kouichi	Characterization of BaSrTiO3/Si and other materials by total reflection XAFS	BL16B2
C99B16B2-416N	HIRAI, Yasuharu	Analysis of local structure of magnetic materials	BL16B2
C99B16B2-417N	OKAMOTO, Tokuhiko	XAFS Study on Local Structure of Ce and Zr in Industrial Catalysts	BL16B2
C99B16B2-418N	KUDO, Yoshihiro	The Structure Analysis of GaN by XAFS Method	BL16B2
C99B24XU-501N	KATSUYA, Yoshio	X-ray Structure Analyses of Isoamylase and Related Enzymes	BL24XU
C99B24XU-502N	KATSUYA, Yoshio	Evaluation of Biocrystallography Experimental Hutch of Hyogo Beamline (BL24XU)	BL24XU
C99B24XU-503N	TERASHIMA, Akira	Study of Phase on Structural Analysis for Bioactive Molecule and Medicine for Brain Function	BL24XU
C99B24XU-504N	TANIGUCHI, Taizo	Structual and functional analysis of the dementia-causing proteins	BL24XU
C99B24XU-505N	KOIKE, Hideaki	Crystallographic study of molecular mechanism of the thermostability of DNA binding proteins	BL24XU
C99B24XU-506N	HARATA, Kazuaki	Study on the mechanism of thermostability of enzymes and proteins	BL24XU
C99B24XU-507N	MISAKI, Shintarou	Crystallographic analysis of intergrase, proteinase and lyase	BL24XU
C99B24XU-508N	MISAKI, Shintarou	Crystallographic analysis of micro crystals I	BL24XU
C99B24XU-509N	YANAGI, Kazunori	Crystallographic analysis of functional organic micro crystals	BL24XU
C99B24XU-510N	FUJISHIMA, Akira	Crystallographic analysis of proteins related to drug-design. III	BL24XU
C99B24XU-511N	FUJISHIMA, Akira	Crystallographic analysis f microcrystals, III	BL24XU
C99B24XU-514N	SHIMA, Hideaki	Crystallographic analysis of helicase from E.coli (section 1)	BL24XU
C99B24XU-515N	SHIMA, Hideaki	Crystallgrahic analysis of micro crystals IV (section 1)	BL24XU
C99B24XU-518N	KOIZUMI, Masahiro	Crystallographic analysis of complex of serine protease inhibitor.	BL24XU
C99B24XU-519N	SUGIO, Shigetoshi	Crystal Structure analysis of Protein Kinase and Protein Phosphatase	BL24XU
C99B24XU-520N	SUGIO, Shigetoshi	Structure Analysis of Phthalocyanine Derivatives with Microcrystals	BL24XU
C99B24XU-521N	SHIROMIZU, Ikuya	Crystallographic analysis of proteins relaed to drug-design VIII (part I)	BL24XU
C99B24XU-523N	MORIKAWA, Kousuke	Crystallographic study of the recombinational DNA repair proteins Ruv A . B. C	BL24XU
C99B24XU-524N	MIYANO, Masashi	Protein structure determination for medicinal development	BL24XU
C99B24XU-525N	MIYANO, Masashi	Small Crystal Structure determination for MES	BL24XU

C99B24XU-528N	KOIZUMI, Masahiro	Crystallographic analysis of synthetic serine protease inhibitors.	BL24XU
C99B24XU-531N	KANEYOSHI, Takahiro	Structual analysis of titan nitrides films using X-ray diffraction method	BL24XU
C99B24XU-532N	WATANABE, Yoshio	In situ observation of crystal surfaces / interfaces during metalorganic chemical vapor deposition	BL24XU
C99B24XU-533N	NAKAGAWA, Shigetomo	In-situ Analysis of Surgace Film Structure on Metal Substrates during Oxidation or Corrosion	BL24XU
C99B24XU-534N	NAKAGAWA, Shigetomo	An analysis procedure for thermal barieer coating	BL24XU
C99B24XU-535N	NAKAGAWA, Shigetomo	Some observations on the surface structure of ion implanted molds for rubber	BL24XU
C99B24XU-541N	MATSUI, Junji	Study of Formation of X-Ray Quasi-Plane-Wave Microbam and Its Application.	BL24XU
C99B24XU-542N	KAGOSHIMA, Yasushi	Formation of the x-ray microbeams using focusing x-ray optical elements and the development of a scanning x-ray microscope	BL24XU
C99B24XU-543N	TSUSAKA, Yoshiyuki	Development of High Resolution X-ray Imaging by the Refraction Contrast Method	BL24XU
C99B24XU-544N	NAKAYAMA, Takenori	Study on Environmental Cracking Mechanism of Structual Materials by SR	BL24XU
C99B24XU-545N	KIMURA, Shigeru	Precise x-ray diffraction measurements for local minute strain using highly parallel x-ray microbeam	BL24XU
C99B24XU-546N	IZUMI, Kouichi	Development of the technique for characterizing electronic materials by phase contrast imaging	BL24XU
C99B24XU-547N	KATOH, Takeo	Study on the surface layers of the silicon wafers.	BL24XU
C99B24XU-548N	TANI, Katsuhiko	Topographic Observation of the Structure of Micro-actuator	BL24XU
C99B24XU-549N	UMEZAWA, Osamu	Characterization of subsurface microstructure and microcrack for metallic materials	BL24XU
C99B24XU-550N	NINOMIYA, Toshio	Fundamental study on application of synchrotron radiation to forensic science	BL24XU
C99B24XU-551N	ZHANG, Yanping	X-Ray refractive lenses for micro-beam technology	BL24XU
C99B24XU-552N	MATSUI, Yousuke	Refraction contrast X-ray imaging of internal structure of power transmission belt	BL24XU
C99B24XU-553N	AIZAWA, Katsuo	Detection of peripheral type lung cancer of nude mice with Synchrotron Radiation and Au-NPe6	BL24XU
C99B24XU-554N	ANDO, Masami	Development of imaging technique using quasi-monochromatic SR with very high parallelity	BL24XU
C99B24XU-555N	TANINO, Kichiya	Synchrotron Radiation-Xray Studies of Improvement on Sic Single Crystal	BL24XU
C99B24XU-556N	SATO, Fumio	Structual modultion of carbides and nitrides by X-ray irradiation using synchrotron radiation	BL24XU